

# **MOSFET**

# OptiMOS<sup>™</sup> 3 Linear FET, 200 V

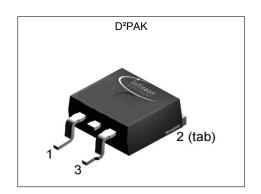
## **Features**

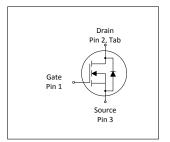
- Ideal for hot-swap and e-fuse applications
- Very low on-resistance R<sub>DS(on)</sub>
  Wide safe operating area SOA
  N-channel, normal level

- 100% avalanche tested
- Pb-free plating; RoHS compliant
  Qualified according to JEDEC<sup>1)</sup> for target applications
  Halogen-free according to IEC61249-2-21



Parameter	Value	Unit
V <sub>DS</sub>	200	V
R <sub>DS(on),max</sub>	11	mΩ
$I_{D}$	88	A
$I_{\text{pulse}} (V_{\text{DS}} = 56 \text{ V}, t_{\text{p}} = 10 \text{ ms})$	8.7	A











Type / Ordering Code	Package	Marking	Related Links
IPB110N20N3LF	PG-TO 263-3	110N20LF	-

# OptiMOS<sup>TM</sup> 3 Linear FET, 200 V



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# OptiMOS<sup>™</sup> 3 Linear FET, 200 V IPB110N20N3LF



1 Maximum ratings at  $T_A$ =25 °C, unless otherwise specified

Table 2 **Maximum ratings** 

Davamatan	O b. a.l	Values					
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain current	ID	- - -	-	88 61 11	A	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C, $R_{\rm thJA}$ =40 K/W <sup>1)</sup>	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	-	-	352	Α	T <sub>C</sub> =25 °C	
Avalanche energy, single pulse <sup>3)</sup>	<b>E</b> AS	-	-	560	mJ	$I_{\rm D}$ =80 A, $R_{\rm GS}$ =25 $\Omega$	
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-	
Power dissipation	P <sub>tot</sub>	-	-	250	W	T <sub>C</sub> =25 °C	
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	150	°C	IEC climatic category; DIN IEC 68-1: 55/150/56	

#### 2 Thermal characteristics

Table 3 **Thermal characteristics** 

Parameter	Cumbal	Values			linit	Note / Test Condition	
Parameter	Symbol	Min. Typ. Max.	Unit	Note / Test Condition			
Thermal resistance, junction - case	R <sub>thJC</sub>	-	0.3	0.5	K/W	-	
Device on PCB, minimal footprint	R <sub>thJA</sub>	-	-	62	K/W	-	
Device on PCB, 6 cm² cooling area <sup>1)</sup>	R <sub>thJA</sub>	-	-	40	K/W	-	

 $<sup>^{1)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.  $^{2)}$  See Diagram 3 for more detailed information  $^{3)}$  See Diagram 13 for more detailed information



## 3 Electrical characteristics

Table 4 Static characteristics

Davissatas	0		Values				
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	200	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	$V_{\rm GS(th)}$	2.2	3.2	4.2	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =260 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	1 10	2 100	μA	V <sub>DS</sub> =160 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =160 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	2 -2	5 -5	μA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V V <sub>GS</sub> =-10 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	9.8	11	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =88 A	
Gate resistance <sup>1)</sup>	R <sub>G</sub>	-	60	90	Ω	-	
Transconductance	<b>g</b> fs	16	31	-	S	$ V_{DS}  > 2 I_D R_{DS(on)max}, I_D = 44 \text{ A}$	

Table 5 Dynamic characteristics<sup>1)</sup>

Davamatav	Sumb al	Values					
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance	C <sub>iss</sub>	-	500	650	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =100 V, f=1 MHz	
Output capacitance	Coss	-	390	510	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =100 V, f=1 MHz	
Reverse transfer capacitance	C <sub>rss</sub>	-	5	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =100 V, f=1 MHz	
Turn-on delay time	$t_{ m d(on)}$	-	6	-	ns	$V_{\rm DD}$ =100 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =44 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Rise time	t <sub>r</sub>	-	70	-	ns	$V_{\rm DD}$ =100 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =44 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Turn-off delay time	$t_{ m d(off)}$	-	79	-	ns	$V_{\rm DD}$ =100 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =44 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Fall time	t <sub>f</sub>	-	26	-	ns	$V_{\rm DD}$ =100 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =44 A, $R_{\rm G,ext}$ =1.6 $\Omega$	

Table 6 Gate charge characteristics<sup>2)</sup>

Parameter	Symbol	Values			Unit	Note / Test Condition	
Parameter	Symbol	Min. Typ. Max.	Ullit	Note / Test Condition			
Gate to source charge	Q <sub>gs</sub>	-	4	-	nC	$V_{DD}$ =100 V, $I_{D}$ =22 A, $V_{GS}$ =0 to 10 V	
Gate to drain charge <sup>1)</sup>	$Q_{gd}$	-	51	-	nC	V <sub>DD</sub> =100 V, I <sub>D</sub> =22 A, V <sub>GS</sub> =0 to 10 V	
Gate charge total <sup>1)</sup>	Qg	-	76	-	nC	$V_{DD}$ =100 V, $I_{D}$ =22 A, $V_{GS}$ =0 to 10 V	
Gate plateau voltage	$V_{ m plateau}$	-	6.8	-	V	V <sub>DD</sub> =100 V, I <sub>D</sub> =22 A, V <sub>GS</sub> =0 to 10 V	
Output charge <sup>1)</sup>	Qoss	-	154	-	nC	V <sub>DD</sub> =100 V, V <sub>GS</sub> =0 V	

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test.  $^{2)}$  See "Gate charge waveforms" for parameter definition

# OptiMOS<sup>TM</sup> 3 Linear FET, 200 V

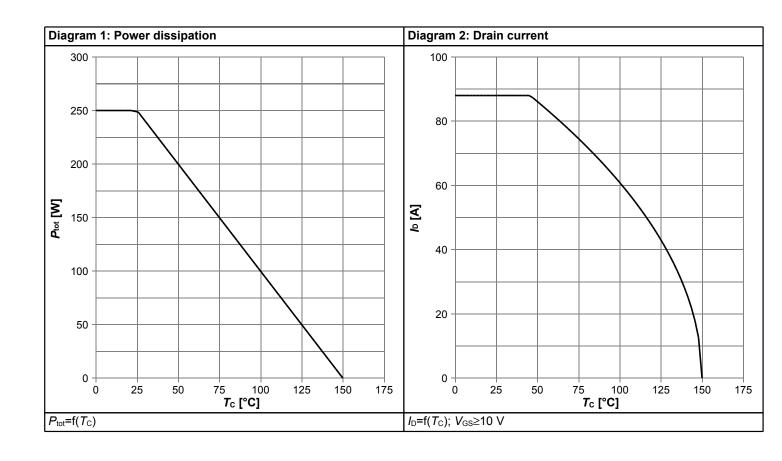


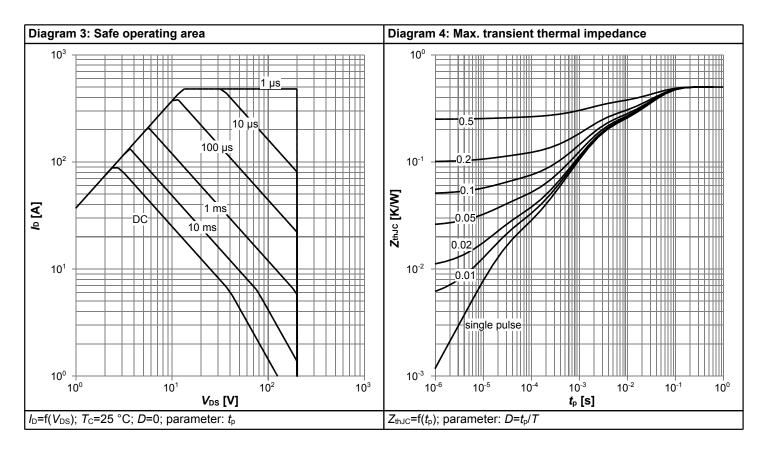
## Table 7 Reverse diode

Davamatar	Cumbal		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continuous forward current	Is	-	-	88	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	352	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode forward voltage	<b>V</b> <sub>SD</sub>	-	0.95	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =88 A, T <sub>j</sub> =25 °C	
Reverse recovery time <sup>1)</sup>	t <sub>rr</sub>	-	145	-	ns	$V_R$ =100 V, $I_F$ =44 A, $di_F/dt$ =100 A/ $\mu$ s	
Reverse recovery charge <sup>1)</sup>	Q <sub>rr</sub>	-	770	-	nC	V <sub>R</sub> =100 V, I <sub>F</sub> =44 A, di <sub>F</sub> /dt=100 A/μs	

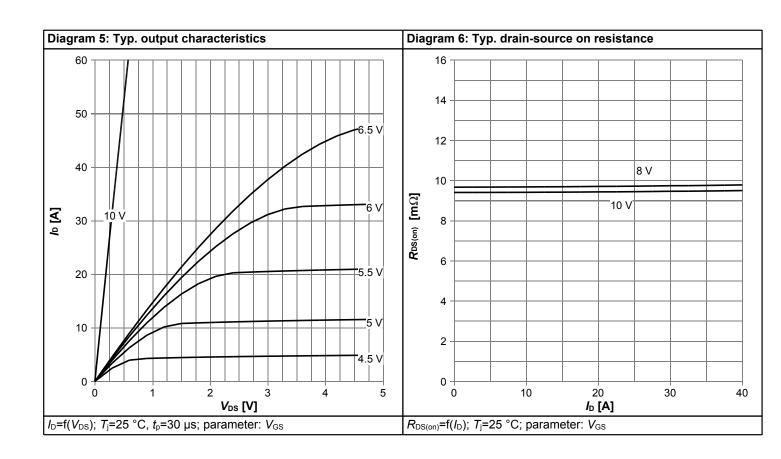


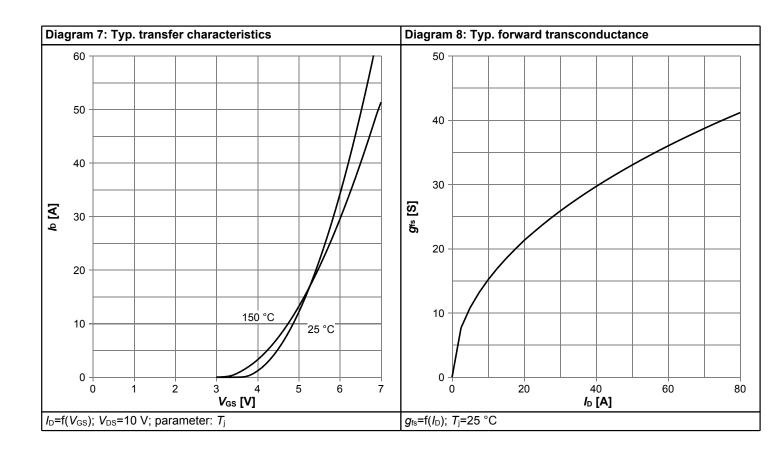
# 4 Electrical characteristics diagrams



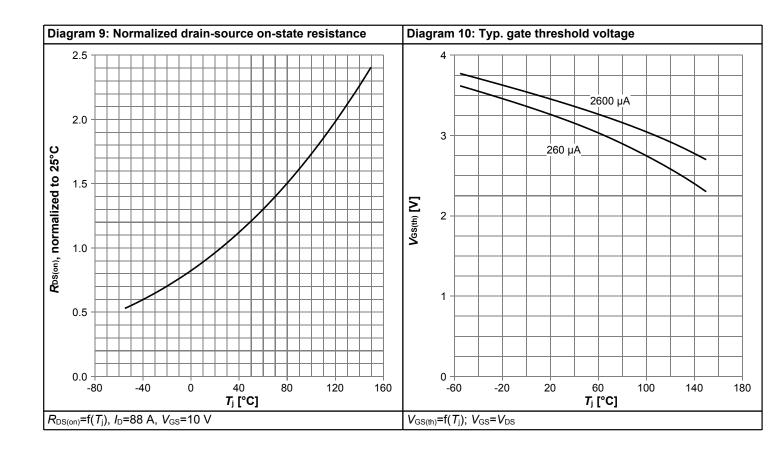


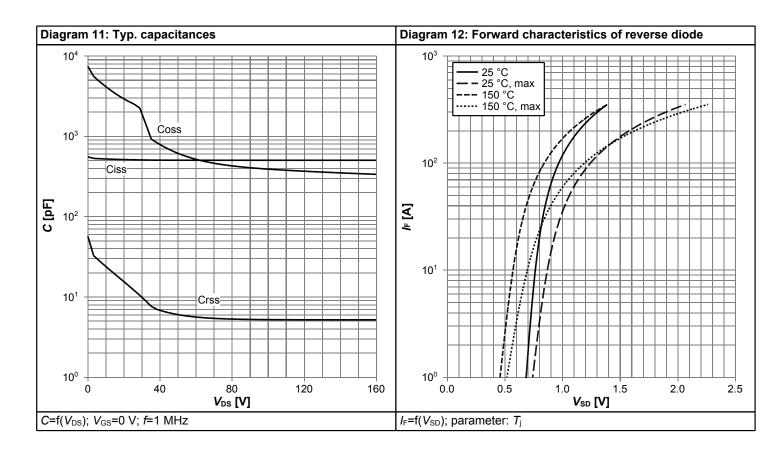




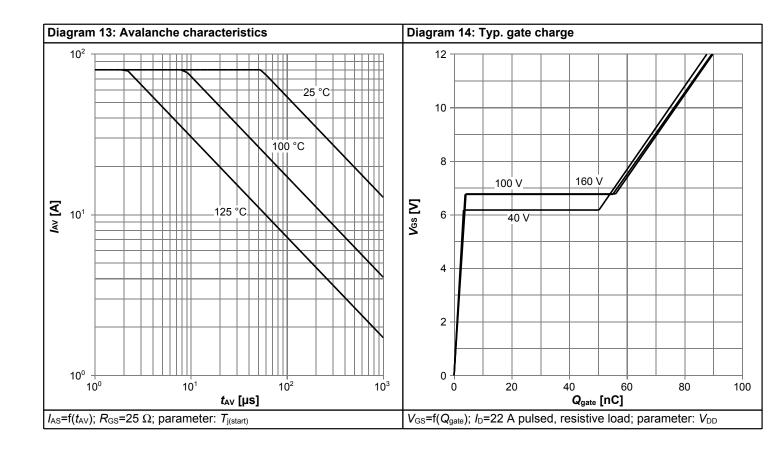


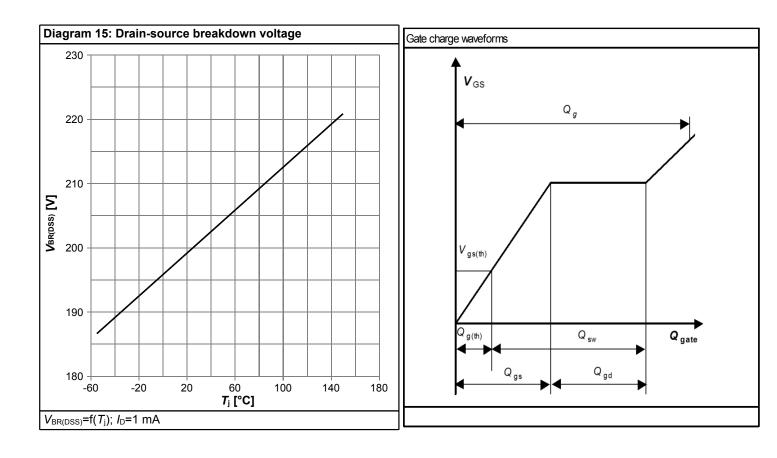






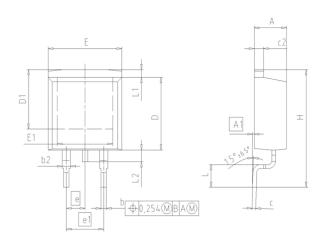


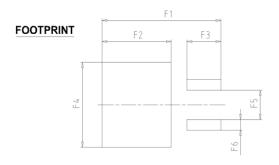






# 5 Package Outlines





DIM	MILLIN	ETERS	INCH	INCHES			
DIM	MIN	MAX	MIN	MAX			
Α	4.30	4.57	0.169	0.180			
A1	0.00	0.25	0.000	0.010			
b	0.65	0.85	0.026	0.033			
b2	0.95	1.15	0.037	0.045			
С	0.33	0.65	0.013	0.026			
c2	1.17	1.40	0.046	0.055			
D	8.51	9.45	0.335	0.372			
D1	7.10	7.90	0.280	0.311			
E	9.80	10.31	0.386	0.406			
E1	6.50	8.60	0.256	0.339			
е	2.5	54	0.100				
e1	5.0	08	0.200				
N		2	2				
Н	14.61	15.88	0.575	0.625			
L	2.29	3.00	0.090	0.118			
L1	0.70	1.60	0.028	0.063			
L2	1.00	1.78	0.039	0.070			
F1	16.05	16.25	0.632	0.640			
F2	9.30	9.50	0.366	0.374			
F3	4.50	4.70	0.177	0.185			
F4	10.70	10.90	0.421	0.429			
F5	3.65	3.85	0.144	0.152			
F6	1.25	1.45	0.049	0.057			

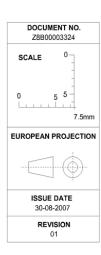


Figure 1 Outline PG-TO 263-3, dimensions in mm/inches

# OptiMOS<sup>™</sup> 3 Linear FET, 200 V IPB110N20N3LF



## **Revision History**

IPB110N20N3LF

Revision: 2017-02-16, Rev. 2.1

## **Previous Revision**

Revision	Date	Subjects (major changes since last revision)
2.0	2016-12-15	Release of final version
2.1	2017-02-16	Update technology heading

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